

# PRODUCT/PROCESS CHANGE NOTIFICATION

PCN MMS-MIC/14/8451 Dated 27 May 2014

STM32F4x 2Mbyte products improvement

#### **Table 1. Change Implementation Schedule**

Forecasted implementation date for change	16-Jun-2014				
Forecasted availability date of samples for customer	26-May-2014				
Forecasted date for <b>STMicroelectronics</b> change Qualification Plan results availability	26-May-2014				
Estimated date of changed product first shipment	16-Jun-2014				

#### **Table 2. Change Identification**

Product Identification (Product Family/Commercial Product)	Products listed below				
Type of change	Product design change				
Reason for change	Product features improvement				
Description of the change	In order to provide improved products features to our customers, ST MCD division is introducing a new die revision.				
Change Product Identification	see indicated below				
Manufacturing Location(s)					

Table 3. List of A	ttachments
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Customer Part numbers list	
Qualification Plan results	

Customer Acknowledgement of Receipt	PCN MMS-MIC/14/8451
Please sign and return to STMicroelectronics Sales Office	Dated 27 May 2014
□ Qualification Plan Denied	Name:
□ Qualification Plan Approved	Title:
	Company:
□ Change Denied	Date:
□ Change Approved	Signature:
Remark	
1	

**47/**.

#### **DOCUMENT APPROVAL**

Name	Function
Colonna, Daniel	Marketing Manager
Buffa, Michel	Product Manager
Narche, Pascal	Q.A. Manager

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# PRODUCT/PROCESS CHANGE NOTIFICATION

### STM32F4x 2Mbyte products improvement

#### **MMS - Microcontrollers Division (MCD)**

Dear Customer,

In order to provide improved products features to our customers, ST MCD division is introducing a new die revision.

#### What is the change?

Changes on STM32F4x 2Mbyte products are described below:

	Actual	New		
Wafer Fab	Rousset 8" (France)	Crolles 12" (France) - change		
		indicated in PCN 8037		
Die revision code	Υ	1		
Bootloader	revision 7.0	revision 9.1 (*1)		
Flexible Memory Controller (FMC)	STM32F42xx & STM32F43xx	Limitation described in STM32F42xx		
	Errata sheet r7	& STM32F43xx Errata sheet r7,		
		section 2.8.6, is fixed.		
		Limitation described in STM32F42xx		
		& STM32F43xx Errata sheet r7,		
		section 2.8.10, is added.		

#### (\*1) Bootloader revision 9.1:

The embedded Bootloader revision 9.1 improves communication interfaces, startup time and system clock. For more details, please refer to Application Note 2606 STM32 Microcontroller system memory boot mode, revision 18.

#### Why?

Product features are improved with this new die revision.

#### When?

The production with this new die revision, will start from week 25 2014.

#### How will the change be qualified?

This change will be qualified using the standard STMicroelectronics Corporate Procedures for Quality and Reliability, in full compliancy with the JESD-47 international standard.

See Qualification plan attached at the end of this document.

#### What is the impact of the change?

- Form: no change

- Fit: no change

- Function: new Bootloader, Flexible Memory Controller (FMC) improved

#### How can the change be seen?

Traceability of the change is ensured by ST internal tools.

The die revision is changing from "Y" to "1". It is marked onto the package of the part.

We remain available to discuss any concern that you may have regarding this Product Change Notification.

With our sincere regards.

#### Michel Buffa

#### Microcontroller Division General Manager

#### List of Commercial products impacted:

- STM32F427VGT6
- STM32F427VIT6
- STM32F427VIT6TR
- STM32F429VET6
- STM32F429VGT6
- STM32F429VIT6
- STM32F429VIT6U
- STM32F437VGT6
- STM32F437VIT6
- STM32F437VIT6TR
- STM32F437VIT6WTR
- STM32F439VGT6
- STM32F439VIT6
- STM32F439VIT6U
- STM32F427ZGT6
- STM32F427ZIT6
- STM32F429ZET6
- STM32F429ZGT6
- STM32F429ZIT6
- STM32F429ZIT6U
- STM32F437ZGT6
- STM32F437ZIT6
- STM32F439ZGT6
- STM32F439ZIT6
- STM32F439ZIT6U
- STM32F439IIT6TR
- STM32F427IGT6
- STM32F427IIT6
- STM32F429IET6
- STM32F429IGT6
- STM32F429IIT6
- STM32F429IIT6U
- STM32F437IGT6
- STM32F437IIT6
- STM32F439IGT6
- STM32F439IIT6
- STM32F439IIT6U
- STM32F427IGH6
- STM32F427IIH6
- STM32F427IIH6TR
- STM32F427IIH6U
- STM32F429IEH6
- STM32F429IGH6
- STM32F429IIH6
- STM32F429IIH6TR
- STM32F429IIH6U
- STM32F437IGH6
- STM32F437IIH6

STM32F437IIH6TR STM32F437IIH6U STM32F439IGH6 STM32F439IIH6 STM32F439IIH6TR STM32F439IIH6U



# STM32F4xx - BIG MANTA – 2M New design revision introduction

# **Reliability Evaluation Plan**

April, 17th 2014

MMS MCD Quality & Reliability Department



# STM32F4xx - Big Manta - 2M - M10 - CR300

## Context :

Introduction of new design revision to correct design limitations present on current cut.

## Impacted packages :

- LQFP14x14 (100L) assembled in AMKOR ATK1
- LQFP20x20 (144L) assembled in AMKOR ATK1
- LQFP24x24 (176L) assembled in ASE
- UFBGA10x10 (176L) assembled in AMKOR ATK4

# Reliability Evaluation Plan (1/2)

## Die oriented trials

Tria	al	Test	Method	Criteria	Conditions	Package	Sample x lot	
	STM32F4xx - BIG MANTA – 2M - M10HS – CR300 - TFBGA216 MU1T							
		LU	0018695 JESD78	N.A	125°C	TFBGA216	6 x 1	
		ESD HBM	ANSI/ESDA/JEDEC JS-001	1500Ω , 100pF	25°C 2kV (class 2)	TFBGA216	3 x 1	
DIE		HTOL	MIL-STD-883 Method 1005 JESD22-A108	125°C , 3.6V 1176h	125°C	TFBGA216	77 x 1	
	≣	EDR	JESD-22A117	10 kcyc Prog + 500h/150°C	Cycling @ 125°C Bake @ 150°C	TFBGA216	77 x 1	
	EDR	JESD-22A117	10 kcyc Prog + 168h/150°C	Cycling @ 25°C Bake @ 150°C	TFBGA216	77 x 1		
	EDR	JESD-22A117	10 kcyc Prog + 168h/150°C	Cycling @ -40°C Bake @ 150°C	TFBGA216	77 x 1		

# Reliability Evaluation Plan (2/2)

## Package oriented trials

Package	Test1	Method	Criteria	Test2	Method	Conditions	Sample x lot
	STM32F4xx - BIG MANTA – 2M - M10HS – CR300 – LQFP14x14 ATK1						
LQFP14x14 100L	ESD CDM	ANSI/ESDSTM5.3.1	25°C Min 250V (Class C3)	N.A.	N.A.	N.A.	3 x 1
	STM	132F4xx - BIG MANTA	– 2M - M10HS	– CR300 – L	QFP20x20 A	TK1	
LQFP20x20 144L	ESD CDM	ANSI/ESDSTM5.3.1	25°C Min 250V (Class C3)	N.A.	N.A.	N.A.	3 x 1
	STM32F4xx - BIG MANTA – 2M - M10HS – CR300 – LQFP24x24 ASE						
LQFP24x24 176L	ESD CDM	ANSI/ESDSTM5.3.1	25°C Min 250V (Class C3)	N.A.	N.A.	N.A.	3 x 1
	STM32F4xx - BIG MANTA – 2M - M10HS – CR300 – UFBGA10x10 ATK4						
UFBGA10x10 176L	ESD CDM	ANSI/ESDSTM5.3.1	25°C Min 250V (Class C3)	N.A.	N.A.	N.A.	3 x 1

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